


<p><i>Search Notes</i></p> 	<p>Application/Control No.</p> <p>10594842</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>MURAKAWA ET AL.</p>
	<p>Examiner</p> <p>Leigh Marie Garbowski</p>	<p>Art Unit</p> <p>2825</p>

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Google, IEEExplore, ACM Portal [all strategies as per IEEExplore attachment]	07/15/2008	LMG
WEST	07/16/2008	LMG
WEST (see search history printout)	02/20/2009	LMG
classes 703, 706, 716 (text search only - see search history printout)	02/20/2009	LMG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
716	2, 4	02/20/2009	LMG
703	13	02/20/2009	LMG
706	13	02/20/2009	LMG

	<p>/L. G./</p> <p>Primary Examiner.Art Unit 2825</p>
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